


<b>Search Notes</b>  	<b>Application/Control No.</b>  10734472	<b>Applicant(s)/Patent Under Reexamination</b>  CHARETTE, MARC F.
	<b>Examiner</b>  Wang, Chang-Yu	<b>Art Unit</b>  1649

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
sequence search: SEQ ID NO:2 and aa. 30-431, aa. 30-292, 292-330, 292-431 of SEQ ID NO:21. See sequence search results in SCORE.	5/19/09	CYW
EAST, STN: search strategy attached (updated)	5/19/09	CYW
Inventor name search: EAST, STN, PALM (updated)	5/19/09	CYW
PLUS search from STIC. See search results in eDAN (4/24/09)	5/19/09	CYW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/C. Y. W. /  
Examiner, Art Unit 1649